

Application No.	Applicant(s)	
10/626,285	CHIU ET AL.	
Examiner	Art Unit	
Joseph L. Williams	2879	

	SEARCHED				
Class	Subclass	Date	Examiner		
445	24	5/2/2004	BAN.		
313	534	5/2/2004	Bunn		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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check parent cases for double patenting	5/2/2004	gw JW